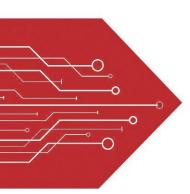
MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

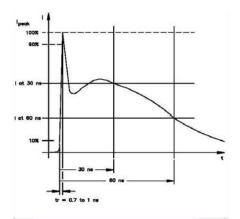
Broduct data speet



1.1 Technology Data	Symbol		Value	Unit
Maximum allowable continuous AC voltage at 50-60Hz	V_{RMS}		18	V
Maximum allowable continuous DC voltage	V_{DC}		5	V
Varistor voltage measured *1	Vv		100~150	V
Typical capacitance value measured at 1MHz	С		0.8	pF
Typical capacitance value tolerance			+80-20	%
Maximum ESD allowable clamping Voltage*2	V_{CLAMP}	<	240	V
Leakage current at V _{DC*3} (At initial state)	I _{LDC}	<	0.1	uA
Leakage current at V _{DC*3} (After ESD Test)	I _{LDCA}	<	2	uA
1.2 Reference Data				
Response time	T_{rise}	<	0.5	ns
Operation ambient temperature			-50∼ + 85	$^{\circ}\!\mathbb{C}$
Storage temperature			-50∼+125	$^{\circ}\! \mathbb{C}$
ESD testing	IEC61000-4-2		Level 4	
1.3 Other Data				
Body			ZnO	
End termination			Ag/Ni/Sn	
Packaging			Reel	
Complies with Standard			IEC61000-4-2	
Complies with RoHs Standard			Yes	
Lead Content		<	1000	ppm
Marking Notes:			None	

Notes:

- $\,st\,$ 1 The varistor voltage was measured at 1 mA current
- * 2 The Clamping voltage was measured at 8*20 us standard current.
- * 3 The Leakage current was measured at working voltage.
- * 4 The Energy only for customer reference.
- * 5 The components shall be employed within 1 year, in the nitrogen condition.



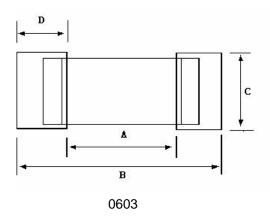
SEVERITY LEVEL	AIRDIRCHARGE	DIRECT
OLVERNIT LEVEL		DISCHARGE
1	2 KV	2 KV
2	4 KV	4 KV
3	8 KV	6 KV
4	15 KV	8 KV

IEC 61000-4-2 Compliant ESD Current Pulse Waveform



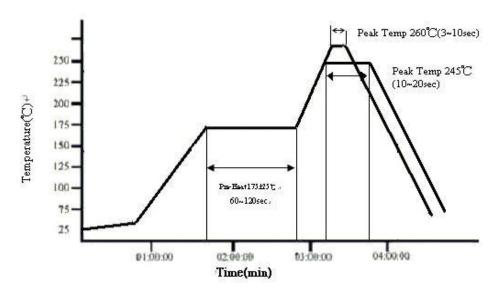


PACKAGE MECHANICAL DATA



Dimension	(Unit:mm)		
	Min.	Max.	
А	0.9	1.2	
В	2.7	3.2	
С	0.7	1.0	
D	0.9	1.2	

The IR reflow and temperature of Soldering for Pb Free



☆ IR reflow Pb Free Process suggestion profile

- (1) The solder recommend is Sn96.5/Ag 3.5 of 120 to 150 μ m
- (2) Ramp-up rate (217°C to Peak) + 3°C/second max
- (3) Temp. maintain at 175 +/-25 $^{\circ}$ C 180 seconds max
- (4) Temp. maintain above 217 °C 60-150 seconds

REEL SPECIFICATION

P/N	PKG	QTY
ESD0603E002M05	0603	4000



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